JETIR.ORG

## ISSN: 2349-5162 | ESTD Year: 2014 | Monthly Issue



## JOURNAL OF EMERGING TECHNOLOGIES AND INNOVATIVE RESEARCH (JETIR)

An International Scholarly Open Access, Peer-reviewed, Refereed Journal

Ref No: JETIR / Vol 7 / Issue 6 / 419

**Confirmation Letter** 

To,

KAMAL NIWARIA

Published in : Volume 7 | Issue 6 | 2020-06-27



Subject: Publication of paper at International Journal of Emerging Technologies and Innovative Research.

Dear Author,

With Greetings we are informing you that your paper has been successfully published in the International Journal of Emerging Technologies and Innovative Research (ISSN: 2349-5162). Following are the details regarding the published paper.

About JETIR : An International Scholarly Open Access Journal, Peer-Reviewed, Refereed

> Journal Impact Factor Calculate by Google Scholar and Semantic Scholar | AI-Powered Research Tool, Multidisciplinary, Monthly, Multilanguage Journal Indexing in All Major Database & Metadata, Citation Generator, Impact Factor:

7.95, ISSN: 2349-5162

UGC Approval: UGC and ISSN Approved - UGC Approved Journal No: 63975 | Link:

https://www.ugc.ac.in/journallist/subjectwisejurnallist.aspx?tid=MjM0OTUxNjI

=&&did=U2VhcmNoIGJ5IElTU04=

Registration ID: JETIR 234627 Paper ID : JETIR2006419

Title of Paper : A Novel Technique for Reduced Peak to Average Power Ratio in

MIMO-OFDM

Impact Factor : 7.95 (Calculate by Google Scholar)

DOI

: Volume 7 | Issue 6 | 2020-06-27 Published in

Publication Date: 2020-06-27 Page No : 564-570

Published URL: http://www.jetir.org/view?paper=JETIR2006419

: KAMAL NIWARIA, Deepak Bhatia, Dr.Bharti Chourasia

Thank you very much for publishing your article in JETIR. We would appreciate if you continue your support and keep sharing your knowledge by writing for our journal JETIR.















International Journal of Emerging Technologies and Innovative Research (ISSN: 2349-5162)

www.jetir.org | editor@jetir.org | Impact Factor: 7.95 (Calculate by Google Scholar)

An International Scholarly Open Access Journal, Peer-Reviewed, Refereed Journal